CHANGE NOTIFICATION



October 01, 2013

Dear Sir/Madam: PCN# 100113

Subject: Notification of Assembly Process Change for LTM8027

Please be advised that Linear Technology Corporation has made a minor change to the internal package construction to facilitate the use of one attach material for both die and components. The die attach material is changed from epoxy to solder, which is already used for attaching components in the same µModule device package. In order to use the solder die attach, the die attach paddle (DAP) has been modified by splitting the DAP into multiple pads for dice Q1, Q2, R3, and R7. Linear has been shipping several µModule devices using solder for die attach and component attach.

Besides these changes, no functional, parametric, mechanical, or datasheet specifications are affected and the component bill of materials remains unchanged. Similarly, there are no changes associated with the package footprint, PCB layout or product top marking, so the customer applications will be unaffected.

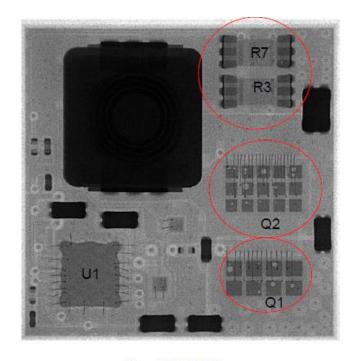
Parts incorporating the new substrate design have been fully characterized and tested for package level reliability. The change was qualified by performing extensive characterization over the full operating voltage and temperature ranges and MSL3 preconditioning. Devices from the same µModule device product families have been subjected to 1000 cycles of temperature cycles and thermal shock. Products built using the improved design are targeted for shipment after December 4th, 2013.

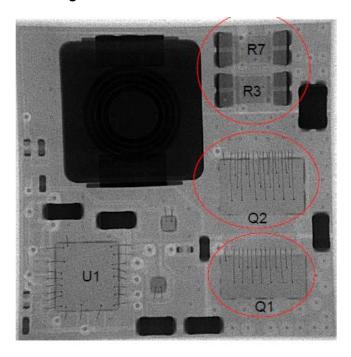
Should you have any further questions, please feel free to contact me at 408-432-1900 ext. 2077, or by E-mail <u>JASON.HU@LINEAR.COM</u>. If I do not hear from you by December 2nd, 2013, we will consider this change approved by your company.

Sincerely,

Jason Hu Quality Assurance Engineer

LTM8027- Current and New Design





New LTM 8027 Old LTM 8027



PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report 8/26/2013 OPERATING LIFE TEST K DEVICE HOURS AT +150°C NUMBER SAMPLE OLDEST NEWEST DATE CODE DATE CODE 8IZE FAILURES LTM8008 1210 77 77.00 • J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK 0 NUMBER SAMPLE OLDEST DEVICE NEWEST SZE DATE CODE DATE CODE FAILURES LTM8001 199 1236 1236 0 LTM8008 462 1210 1210 0 LTM8021 204 1306 1306 0 LTM8023 204 1245 1245 0 LTM8025 204 1245 1245 0 LTM8028 184 1236 1236 0 LTM8029 245 1239 1239 0 LTM8032 204 1302 1302 0 LTM8033 204 1306 1306 0 LTM8045 152 1225 1225 0 LTM8047 77 1242 1242 0 LTM8048 274 1232 1236 0 LTM8052 358 1239 1239 0 LTM8058 204 1239 1239 0 LTM8061 1309 1309 0 3,380 0 HIGH TEMPERATURE BAKE at 150°C K DEVICE HOURS AT +150°C DEVICE **SAMPLE** OLDEST DATE CODE NEWEST DATE CODE **FAILURES** LTM8001 25 1236 1236 25.00 LTM8008 77 1210 1210 77.00 0 LTM8021 50 1306 1306 50.00 0 LTM8023 50 1245 1245 50.00 0 LTM8025 50 1245 1245 50.00 0 LTM8029 50 1239 1239 50.00 0 74 0 LTM8032 1302 1302 74.00 LTM8033 77 1306 1306 77.00 0 LTM8045 50 0 1225 1225 50.00 LTM8052 50 1239 1239 50.00 0 LTM8058 50 1239 1239 50.00 0 603.00 603 0 HIGHLY ACCELERATED STRESS TEST (+131°C/85%R.H. w BIAS) K DEVICE HOURS AT +85°C NUMBER DEVICE OLDEST DATE CODE NEWEST DATE CODE OF FAILURES LTM8008 46 1210 1210 88.32 0 46 88.32 0 UNBIASED HIGHLY ACCELERATED STRESS TEST (+131°C/85%R.H.) NUMBER K DEVICE DEVICE SAMPLE OLDEST NEWEST HOURS AT +131°C SIZE DATE CODE DATE CODE **FAILURES** LTM8001 43 1236 1236 4.13 0 LTM8023 50 1245 1245 4.80 0 LTM8025 50 1245 1245 4.80 0 LTM8028 30 1236 1236 2.88 0 LTM8029 70 1239 1239 6.72 0 LTM8032 50 1302 1302 4.80 0 LTM8033 50 1306 1306 4.80 0 LTM8045 49 1225 1225 8.23 0 LTM8052 50 1239 1239 4.80 0 0 LTM8058 50 1239 1239 4.80 LTM8061 50 1309 1309 4.80 0 588 57.77 0



PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report 9/19/2013 TEMPERATURE/HUMIDITY STORAGE (+85°C/85%R.H.) (1) K DEVICE HOURS AT +85°C NUMBER SAMPLE OLDEST NEWEST OF FAILURES SIZE DATE CODE DATE CODE LTM8008 1210 1210 77.00 0 77 TEMP CYCLE FROM -65°C to +150°C (1) NUMBER DEVICE SAMPLE OLDEST NEWEST CYCLES DATE CODE DATE CODE FAILURES LTM8008 231 231.00 1210 1210 0 LTM8032 77 1302 1302 77.00 LTM8033 77 1306 1306 77.00 0 LTM8052 77 1239 1239 77.00 0 LTM8061 1309 1309 77.00 0 539 539.00 0 TEMP CYCLE FROM -55°C to +125°C (*) NUMBER SAMPLE SIZE NEWEST DATE CODE K DEVICE CYCLES DEVICE OLDEST DATE CODE OF FAILURES LTM8001 1236 1236 77.00 LTM8021 77 1306 1306 77.00 0 LTM8023 77 1245 1245 77.00 0 LTM8025 77 1245 1245 0 77.00 LTM8028 77 1236 1236 77.00 0 77 1239 1239 77.00 0 LTM8029 LTM8045 77 1225 1225 77.00 0 77 LTM8047 1242 1242 77.00 0 LTM8048 102 1232 1236 140.50 0 LTM8052 77 1239 1239 77.00 0 LTM8058 77 1239 1239 77.00 0 872 910.50 THERMAL SHOCK FROM -65°C to +150°C (1) NUMBER DEVICE SAMPLE SIZE NEWEST DATE CODE K DEVICE CYCLES **FAILURES** LTM8008 231 1210 1210 231.00 0 LTM8032 77 1302 1302 77.00 0 LTM8033 77 1306 1306 77.00 0 LTM8052 77 1239 1239 77.00 0 LTM8061 1309 38.50 77 1309 0 500.50 539 THERMAL SHOCK FROM -55°C to +125°C (1) K DEVICE CYCLES NUMBER DEVICE DATE CODE DATE CODE SAMPLE FAILURES LTM8001 1236 1236 77.00 0 LTM8021 77 1306 1306 77.00 0 LTM8023 77 1245 1245 77.00 0 LTM8025 77 1245 1245 77.00 0 LTM8028 77 1236 1236 77.00 0 LTM8029 77 1239 1239 77.00 0 LTM8045 75 1225 1225 75.00 0 LTM8048 126 1232 1236 126.00 0 LTM8052 77 1239 1239 77.00 0 LTM8058 77 1239 1239 77.00 О 817 817.00 BOARD MOUNT TEMP CYCLE FROM -40°C to +125°C NUMBER DEVICE CYCLES SAMPLE DATE CODE DATE CODE FAILURES LTM8008 1210 1210 22.50 15 22.50 15 О (1) Environmental stress are preceded by JEDEC Level 3 Preconditioning: 192h 30°C/60% R.H. soak, followed by 3x

Reflow at 245°C